



Liquid Chemicals Global Technical Committee Japan TC Chapter

Meeting Summary and Minutes

Japan Standards Spring Meetings 2024
 Friday May 24, 2024, 15:00 -17:00(JST)
 SEMI Japan office, Tokyo, Japan via OVTCCM (Hybrid)

TC Chapter Announcements

Next TC Chapter Meeting

Friday, December 6, 2024 15:00~17:00 [JST]

SEMI Japan office Room1, Tokyo, Japan via OVTCCM (Hybrid)

Table 1 Meeting Attendees

Italics indicate virtual participants

Co-Chairs: Yoshiyuki Fujitani (SCREEN Semiconductor Solutions), Takuya Nagafuchi (Nihon Entegris)

SEMI Staff: Hiroshi Sato

<i>Company</i>	<i>Last</i>	<i>First</i>	<i>Company</i>	<i>Last</i>	<i>First</i>
Advance Electric Co., Inc.	Sasao	Kimihito	Particle Measuring Systems, Inc.	Takeshita	Mitsuyoshi
AIST-National Institute of Advanced Industrial and Technology	Kato	Haruhisa	RION CO., LTD.	Kondo	Kaoru
CKD Corporation	Yamaguchi	Tomoya	RION CO., LTD.	Shimmura	Masaki
Nihon Entegris G.K.	Nagafuchi	Takuya	SCREEN Semiconductor Solutions Co., Ltd.	Araki	Hiroyuki
Nippon Pillar Packing Co., Ltd.	Koike	Tomoyuki	SCREEN Semiconductor Solutions Co., Ltd.	Fujitani	Yoshiyuki
<i>Nippon Pillar Packing Co., Ltd.</i>	<i>Minato</i>	<i>Yoji</i>	Tokyo Dylec Corp	Yanagiuchi	Mamoru
<i>Nippon Steel Stainless Steel Pipe Co., Ltd.</i>	<i>Miyahara</i>	<i>Osamu</i>			
Organo Corporation	Sugawara	Hiroshi	SEMI Japan	Kanno	Hirofumi
Pall Corporation	Nakagawa	Hisashi	SEMI Japan	Sato	Hiroshi

Table 2 Leadership Changes

<i>WG/TF/SC/TC Name</i>	<i>Previous Leader</i>	<i>New Leader</i>
None		

Table 3 TC Chapter Structure Changes

<i>Previous WG/TF/SC Name</i>	<i>New WG/TF/SC Name or Status Change</i>
	Valve & Fitting Task Force

Table 4 Ballot Results

<i>Document #</i>	<i>Document Title</i>	<i>Committee Action</i>
None		

#1 **Passed** ballots and line items will be submitted to the ISC Audit & Review Subcommittee for procedural review.

#2 **Failed** ballots and line items were returned to the originating task forces for re-work and re-balloting or abandoning.

Table 5 Ratification Ballot Results

<i>Document #</i>	<i>Document Title</i>	<i>ISC A&R Action</i>	<i>A&R Forms</i>
None			

Note 1: **Passed** Ratification ballots will be submitted to SEMI publication for final processing.

Note 2: **Failed** Ratification ballots were returned to the originating task forces for re-work and re-balloting or abandoning.

Table 6 Activities Approved by the GCS between meetings of the TC Chapter

<i>#</i>	<i>Type</i>	<i>SC/TF/WG</i>	<i>Details</i>
None			

Table 7 Authorized Activities

Listing of all revised or new SNARF(s) approved by the Originating TC Chapter.

<i>#</i>	<i>Type</i>	<i>SC/TF/WG</i>	<i>Details</i>
---	TFOF	TF	Valve & Fitting Task Force [NEW]
7255	SNARF	Liquid Filter TF	SNARF for Revision of SEMI C89 - Test Method for Particle Removal Performance of Liquid Filter Rated Below 30 nm with Inductively Coupled Plasma – Mass Spectroscopy (ICP-MS)
7254	SNARF	Liquid Filter TF	SNARF for Revision of F110-0712 (Reapproved 0618) Test Method for Mono-Dispersed Polystyrene Latex (PSL) Challenge of Liquid Filters

#1 SNARFs and TFOFs are available for review on the SEMI Web site at:

<http://downloads.semi.org/web/wstdsbal.nsf/TFOFSNARE>

Table 8 Authorized Ballots

<i>#</i>	<i>When</i>	<i>TF</i>	<i>Details</i>
7255	Cycle-6 and beyond	Liquid Filter TF	Ballot 7255 for Revision of SEMI C89 - Test Method for Particle Removal Performance of Liquid Filter Rated Below 30 nm with Inductively Coupled Plasma – Mass Spectroscopy (ICP-MS) in Cycle-6 and beyond

Table 9 SNARF(s) Granted a One-Year Extension

<i>#</i>	<i>TF</i>	<i>Title</i>	<i>Expiration Date</i>
None			

Table 10 SNARF(s) Abolished

<i>#</i>	<i>TF</i>	<i>Title</i>
None		

Table 11 Standard(s) to receive Inactive Status

<i>Standard Designation</i>	<i>Title</i>
None	

Table 12 New Action Items

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
None		

Table 13 Previous Meeting Action Items

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
20231208-3	Kimihito Sasao	To prepare a TFOF within 6 months → done
20231208-1	SEMI Staff	To correct references to the Committee and Region of SEMI C105 in SEMI Standards Publications Section of the Staff Report. → done
20231208-2	SEMI Staff	To tell SEMI HQ to change the originating Region of SEMI C82-0713 (Reapproved 0819) and SEMI C89-0116 from America to Japan as well as the Initiating Region. → done

1 Welcome, Reminders, and Introductions

Takuya Nagafuchi (Nihon Entegris G.K.) called the meeting to order at 15:00. The meeting reminders on antitrust issues, intellectual property issues and holding meetings with international attendance were reviewed. Attendees introduced themselves.

Attachment: 01_Meeting Reminders

2 Review of Previous Meeting Minutes

The TC Chapter reviewed the minutes of the previous meeting.

Motion: Approve the minutes as written

By / 2nd: Yoshiyuki Fujitani (SCREEN Semiconductor Solutions Co., Ltd.) / Hisashi Nakagawa (Pall Corporation)

Discussion: None

Vote: 14-Y 0-N. **Motion Passed.**

Attachment: 02_Liquid Mins_231208_approved

3 Liaison Reports

3.1 Liquid Chemicals North America TC Chapter

Hirofumi Kanno (SEMI Japan) reported for the NA TC Chapter. Of note:

- Ten ballots have resulted in the passage of the SEMI C90-1015 test method revision, while the remaining ones have Failed.
- The GCS approved the ballots for Doc. 6601 and Doc. 7087, and as a new SNARF, a revision to SEMI F41-1116 was also approved. In particular, Doc. 6601 is a new standard.



Attachment: 03_NA LChem Liaison Report Mar2024 v1

3.2 Europe TC Chapter Gases & Liquid Chemicals Joint Global Technical Committee

Hirofumi Kanno (SEMI Japan) reported for the Europe TC Chapter. Of note:

- The most recent Europe committee meeting was held in November 2023 and the Japan committee meeting was held in December 2023, so these minutes have already been reported.

Attachment: 04_EU Gases & Liquid Chemicals Liaison Report Dec2023 v1

4 SEMI Staff Report

Hirofumi Kanno (SEMI Japan) gave the SEMI Staff Report. Of note:

- New online voting system went live for Cycle 3, 2024. This integrates and streamlines sign-in process with various SEMI/Standards member services, and improves data management for SEMI internal database. It is also expected to bring updated user interface while maintaining functionality that's familiar to voters.
- SEMI Standards Regulations and Procedure Manual were updated in February 2024. They are available at www.semi.org/standards (under Tools for Developing Standards).
- TFs have one year from 02/20/24 to implement use of Connect@SEMI (<https://connect.semi.org>) for TF management and document development depository. Once TFs have implemented use of Connect@SEMI, they shall use it to: maintain the TF member roster up to date, share the working drafts in PDF, and distribute the Draft Document at least one week before ballot submission to SEMI.
- Meeting Required Elements have been updated to include notice on confidential information.

Attachment: 05_Staff Report March 2024

5 Ballot Review

None

6 Subcommittee and Task Force Reports

6.1 Liquid Filter TF

Hisashi Nakagawa (Pall Corporation) reported for the *Liquid Filter* Task Force.

- Doc. 7255, Revision of SEMI C89-0116 TEST METHOD FOR MEASURING PARTICLE REMOVAL PERFORMANCE OF LIQUID FILTERS RATED BELOW 30 nm BY INDUCTIVELY COUPLED PLASMA - MASS Regarding "SPECTROSCOPY (ICP-MS)", the Task Force have prepared the draft of the current revised background and methods based on comments and asked for comments, but there were no particular opinions so the Task Force will ballot in Cycle 6, beyond.
- Doc. 7254, Revision of SEMI F110-0712: TEST METHOD FOR MONODISPERSED POLYSTYRENE LATEX (PSL) CHALLENGE OF LIQUID FILTERS, the Task Force added to the scope on comments that were in the SNARF review for the F110 revision last year.

Attachment: 06_LF-TF Meeting Minutes_20240524_handout_delivered



6.2 Liquid-Borne Particle Counter TF

-- Masaki Shinmura (RION CO., LTD.) reported for the Liquid-Borne Particle Counter Task Force.

With respect to the 5-year review of C77-0818 TEST METHOD FOR DETERMINING THE COUNTING EFFICIENCY OF LIQUIDBORNE PARTICLE COUNTERS FOR WHICH THE MINIMUM DETECTABLE PARTICLE SIZE IS BETWEEN 30 NM AND 100 NM., the Task Force are addressing and improving upon the negative comments that arose during the last ballot, and are aiming to introduce a ballot for Cycle 7.

Attachment: 07_20240524_SEMI LC TC LPC TF report

6.3 Trace Metal Analysis for High Pure IPA TF

None

7 Old Business

7.1 SNARF Project Period Check

None

7.2 5-year Review

7.2.1 SEMI F110-0712 (Reapproved 0618), Test Method for Mono-Dispersed Polystyrene Latex (PSL) Challenge of Liquid Filters

→ The response to this standard was addressed in 8.4 New Business.

7.2.2 SEMI C89-0116, Test Method for Particle Removal Performance of Liquid Filter Rated Below 30 nm with Inductively Coupled Plasma – Mass Spectroscopy (ICP-MS)

→ The response to this standard was addressed in 8.2 New Business.

7.2.3 SEMI C77-0818, Test Method for Determining the Counting Efficiency of Liquid-Borne Particle Counters for Which the Minimum Detectable Particle Size is Between 30 nm and 100 nm

→ This standard was explained in 6.2 Liquid-Borne Particle Counter TF Report.

Attachment: 08_LC_5-year Review_searchresults

8 New Business

8.1 Valve and Fitting Task Force

Motion: Approve the TFOF

By / 2nd: Kimihito Sasao (Advance Electric Co., Inc.) / Mitsuyoshi Takeshita (Particle Measuring Systems, Inc.)

Discussion: None

Vote: 14-Y 0-N. **Motion Passed.**

Attachment: 09_TFOF_May 2024 Valve Fitting Japan



8.2 Revision of SEMI C89 - Test Method for Particle Removal Performance of Liquid Filter Rated Below 30 nm with Inductively Coupled Plasma – Mass Spectroscopy (ICP-MS)

Motion: Approve the SNARF for Revision of SEMI C89 - Test Method for Particle Removal Performance of Liquid Filter Rated Below 30 nm with Inductively Coupled Plasma – Mass Spectroscopy (ICP-MS)
By / 2nd: Hisashi Nakagawa (Pall Corporation) / Kimihito Sasao (Advance Electric Co., Inc.)
Discussion: None
Vote: 14-Y 0-N. **Motion Passed.**

Attachment: 10_C89_SNARF_20240524

8.3 Doc. 7255 for Revision of SEMI C89 - Test Method for Particle Removal Performance of Liquid Filter Rated Below 30 nm with Inductively Coupled Plasma – Mass Spectroscopy (ICP-MS) in Cycle-6 and beyond

Motion: Authorize the Doc.7255 for Letter Ballot in Cycle-6 and beyond
By / 2nd: Hisashi Nakagawa (Pall Corporation) / Kimihito Sasao (Advance Electric Co., Inc.)
Discussion: None
Vote: 13-Y 0-N. **Motion Passed.**

8.4 Doc. 7254 for Revision of F110-0712 (Reapproved 0618) Test Method for Mono-Dispersed Polystyrene Latex (PSL) Challenge of Liquid Filters

Motion: Approve the SNARF for Revision of F110-0712 (Reapproved 0618) Test Method for Mono-Dispersed Polystyrene Latex (PSL) Challenge of Liquid Filters
By / 2nd: Hisashi Nakagawa (Pall Corporation) / Kimihito Sasao (Advance Electric Co., Inc.)
Discussion: None
Vote: 13-Y 0-N. **Motion Passed.**

Attachment: 11_F110_SNARF_Revised_20240524

9 Next Meeting and Adjournment

Friday, December 6, 2024 15:00~17:00 [JST], SEMI Japan office Room1, Tokyo, Japan via OVTCCM (Hybrid)

See <http://www.semi.org/standards-events> for the current list of events.

Adjournment: [17:00]>.

Respectfully submitted by:

Hiroshi Sato

Standards & EHS

SEMI Japan

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Minutes tentatively approved by:

Yoshiyuki Fujitani (SCREEN Semiconductor Solutions Co., Ltd.), Co-chair	
Takuya Nagafuchi (Nihon Entegris G.K.), Co-chair	

Table 14 Index of Available Attachments^{#1}

<i>Title</i>	<i>Title</i>
01_Meeting Reminders	07_20240524_SEMI LC TC LPC TF report
02_Liquid Mins_231208_approved	08_LC_5-year Review_searchresults
03_NA LChem Liaison Report Mar2024 v1	09_TFOF_May 2024 Valve Fitting Japan
04_EU Gases & Liquid Chemicals Liaison Report Dec2023 v1	10_C89_SNARF_20240524
05_Staff Report March 2024 v4.2	11_F110_SNARF_Revised_20240524
06_LF-TF Meeting Minutes_20240524_handout_delivered	

#1 Due to file size and delivery issues, attachments must be downloaded separately. A .zip file containing all attachments for these minutes is available at www.semi.org. For additional information or to obtain individual attachments, please contact [SEMI Staff Name] at the contact information above.